



Advanced Technologies in Electromagnetic Compatibility

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Message from the Guest Editors

EMC rules the maximum emission levels and the minimum immunity requirements for the devices at the scope to ensure their correct interoperability in the real operational environment. The EMC field studies the effect of the non-ionizing radiations and it establishes the physical quantities involved in such phenomena and their biological effect in function of the exposure values.

EMC is in evolution and it faces new fields of application. All the topics will be investigated. The use of reverberation chambers has grown in importance and its use is ruled by international standards.

The increasing use of electric or hybrid vehicles suggest the issue of safety assessment in car electric recharging, in particular in regards to the wireless transfer protocol.

More traditional topics, as shielding, absorbing, and gasketing are a subject, because new materials and techniques are being developed, as are the procedures to measure their performances. Nano- and meta-materials are topics that are evolving in the aim of solving these issues.

Finally, attention should be focused on EMC in medical environment, where both devices and human have restrictions aimed to ensure higher levels of safety.





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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